

STD15N50M2AG

Automotive-grade N-channel 500 V, 0.336 Ω typ., 10 A MDmesh™ M2 Power MOSFET in a DPAK package

Datasheet - production data

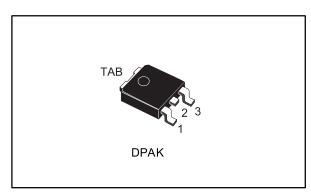
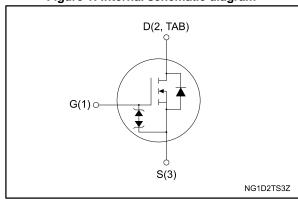


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max.	I _D	Ртот
STD15N50M2AG	500 V	0.380 Ω	10 A	85 W

- Designed for automotive applications and AEC-Q101 qualified
- Extremely low gate charge
- Excellent output capacitance (Coss) profile
- 100% avalanche tested
- Zener-protected

Applications

Switching applications

Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

Table 1: Device summary

Order code	Marking	Package	Packing
STD15N50M2AG	15N50M2	DPAK	Tape and reel

Contents STD15N50M2AG

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STD15N50M2AG Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _G s	Gate-source voltage	±30	V
1-	Drain current (continuous) at T _{case} = 25 °C	10	۸
ID	Drain current (continuous) at T _{case} = 100 °C	7	А
I _{DM} ⁽¹⁾	Drain current (pulsed)	40	Α
P _{TOT}	Total dissipation at T _{case} = 25 °C	85	W
dv/dt ⁽²⁾	Peak diode recovery voltage slope	10	V/ns
dv/dt ⁽³⁾	MOSFET dv/dt ruggedness	25 V	
T _{stg}	Storage temperature range	FF to 1F0	°C
Tj	Operating junction temperature range	-55 to 150	

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max.	1.47	0000
R _{thj-pcb} ⁽¹⁾	Thermal resistance junction-pcb max.	50	°C/W

Notes:

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR} ⁽¹⁾	Avalanche current, repetitive or not repetitive	3.5	Α
E _{AS} ⁽²⁾	Single pulse avalanche energy	200	mJ

Notes:

⁽¹⁾ Pulse width is limited by safe operating area.

 $^{^{(2)}}$ $I_{SD} \leq$ 10 A, di/dt=800 A/µs; V_{DS} peak < $V_{(BR)DSS}, V_{DD}$ = 80% $V_{(BR)DSS}$

 $^{^{(3)}}$ V_{DS} ≤ 400 V.

⁽¹⁾When mounted on a 1 inch² FR-4, 2 Oz copper board

 $^{^{(1)}}$ pulse width limited by T_{jmax}

 $^{^{(2)}}$ starting T_j = 25 °C, I_D = $I_{AR},\,V_{DD}$ = 50 V.

Electrical characteristics STD15N50M2AG

2 Electrical characteristics

(T_{case} = 25 °C unless otherwise specified)

Table 5: Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	500			V
Zana mata walta na dinain		$V_{GS} = 0 \text{ V}, V_{DS} = 500 \text{ V}$			1	
I _{DSS} Zero gate voltage drain current	V _{GS} = 0 V, V _{DS} = 500 V, T _{case} = 125 °C			100	μΑ	
Igss	Gate-body leakage current	V _{DS} = 0 V, V _{GS} = ±25 V			±5	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	2	3	4	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 5 A		0.336	0.380	Ω

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		-	530	ı	
Coss	Output capacitance	V _{DS} = 100 V, f = 1 MHz,	-	33	ı	pF
Crss	Reverse transfer capacitance	Ves = 0 V	-	0.8	-	ρ.
Coss eq. (1)	Equivalent output capacitance	V _{DS} = 0 to 400 V, V _{GS} = 0 V	-	125	1	pF
Rg	Intrinsic gate resistance	f = 1 MHz, I _D = 0 A	-	6.9	-	Ω
Qg	Total gate charge	$V_{DD} = 400 \text{ V}, I_{D} = 9 \text{ A},$	-	13	-	
Q _{gs}	Gate-source charge	V _{GS} = 10 V (see Figure 15: "Test circuit for gate charge	-	2.8	-	nC
Q_{gd}	Gate-drain charge	behavior")	-	5.1	-	

Notes:

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	V _{DD} = 250 V, I _D = 4.5 A	ı	10	ı	
tr	Rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$ (see Figure 14: "Test circuit for	-	3.2	-	
t _{d(off)}	Turn-off delay time	resistive load switching times"	-	84	-	ns
t _f	Fall time	and Figure 19: "Switching time waveform")	1	8.8	1	

 $^{^{(1)}}$ Coss eq. is defined as a constant equivalent capacitance giving the same charging time as Coss when VDs increases from 0 to 80% VDss.

2.7

17.5

μC

Α

Symbol Parameter Test conditions Min. Тур. Max. Unit Source-drain current 10 Α IsD Source-drain current I_{SDM}⁽¹⁾ Α 40 (pulsed) $V_{SD}^{(2)}$ Forward on voltage $V_{GS} = 0 V$, $I_{SD} = 10 A$ 1.6 V $I_{SD} = 9 A$, $di/dt = 100 A/\mu s$, _ 230 t_{rr} Reverse recovery time ns V_{DD} = 100 V (see *Figure 16*: Q_{rr} Reverse recovery charge 2 μC "Test circuit for inductive load switching and diode recovery I_{RRM} Reverse recovery current 17.4 Α times") $I_{SD} = 9 A$, $di/dt = 100 A/\mu s$, t_{rr} Reverse recovery time _ 310 ns

 $V_{DD} = 100 \text{ V}, T_j = 150 ^{\circ}\text{C}$ (see

Figure 16: "Test circuit for inductive load switching and

diode recovery times")

Table 8: Source-drain diode

Notes:

 Q_{rr}

 I_{RRM}

Reverse recovery charge

Reverse recovery current

Table 9: Gate-source Zener diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)GSO}	Gate-source breakdown voltage	$I_{GS} = \pm 250 \ \mu A, \ I_{D} = 0 \ A$	±30	-	-	V

The built-in back-to-back Zener diodes are specifically designed to enhance the ESD performance of the device. The Zener voltage facilitates efficient and cost-effective device integrity protection, thus eliminating the need for additional external componentry.

⁽¹⁾ Pulse width is limited by safe operating area.

⁽²⁾ Pulse test: pulse duration = 300 μ s, duty cycle 1.5%.

2.1 Electrical characteristics (curves)

Figure 2: Safe operating area $t_p = 1 \ \mu s$ Operation in this area is limited by RDS(on) $t_p = 100 \ \mu s$ $t_p = 100 \ m s$

Figure 4: Output characteristics

I_D(A)

20

V_{GS}=8,9,10V

V_{GS}=7V

16

12

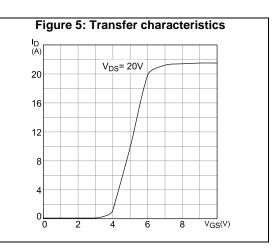
V_{GS}=6V

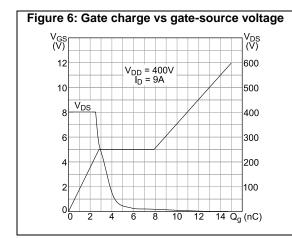
V_{GS}=5V

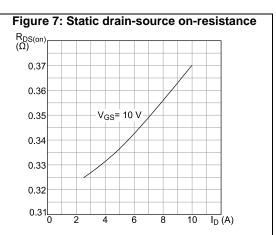
8

4

0
0
4
8
12
16
V_{DS}(V)







STD15N50M2AG Electrical characteristics

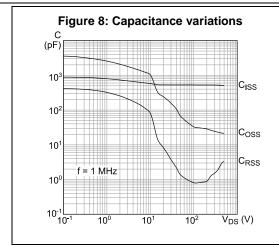


Figure 9: Normalized gate threshold voltage vs temperature

V_{GS(th)}
(norm.)

1.1

1.0

0.9

0.8

0.7

0.6

-75

-25

25

75

125

T_J(°C)

Figure 10: Normalized on-resistance vs temperature

RDS(on) (norm.)

2.2

1.8

1.4

1.0

0.6

0.5

75

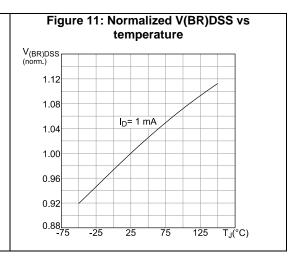
-25

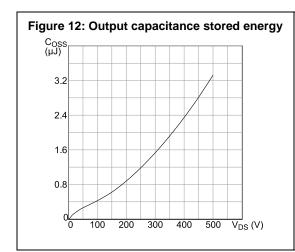
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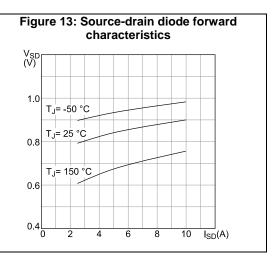
75

125

TJ(°C)







Test circuits STD15N50M2AG

3 Test circuits

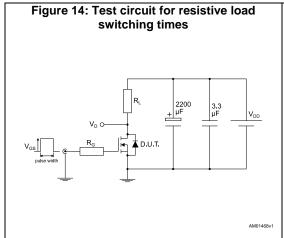


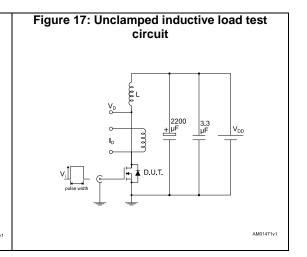
Figure 15: Test circuit for gate charge behavior

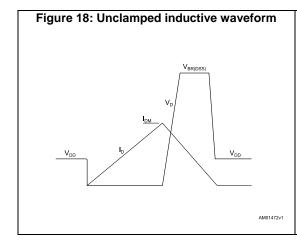
12 V 47 kΩ 100 nF 1 kΩ

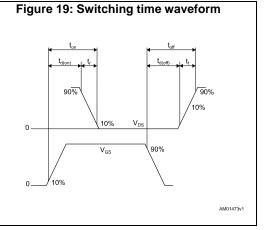
Vos 1 kΩ 1 kΩ

AM01469v1

Figure 16: Test circuit for inductive load switching and diode recovery times







STD15N50M2AG Package information

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

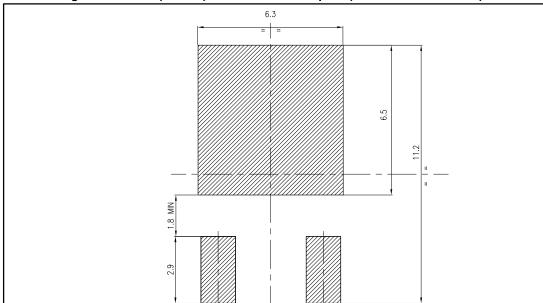
4.1 DPAK (TO-252) type A2 package information

Figure 20: DPAK (TO-252) type A2 package outline E -THERMAL PAD c2 - *E1* -L2 D **b**(2x) R C SEATING PLANE <u>A2</u> (L1) *V2* GAUGE PLANE 0,25 0068772_type-A2_rev21

Table 10: DPAK (TO-252) type A2 mechanical data

Dim	mm				
Dim.	Min.	Тур.	Max.		
A	2.20		2.40		
A1	0.90		1.10		
A2	0.03		0.23		
b	0.64		0.90		
b4	5.20		5.40		
С	0.45		0.60		
c2	0.48		0.60		
D	6.00		6.20		
D1	4.95	5.10	5.25		
Е	6.40		6.60		
E1	5.10	5.20	5.30		
е	2.16	2.28	2.40		
e1	4.40		4.60		
Н	9.35		10.10		
L	1.00		1.50		
L1	2.60	2.80	3.00		
L2	0.65	0.80	0.95		
L4	0.60		1.00		
R		0.20			
V2	0°		8°		

Package information STD15N50M2AG



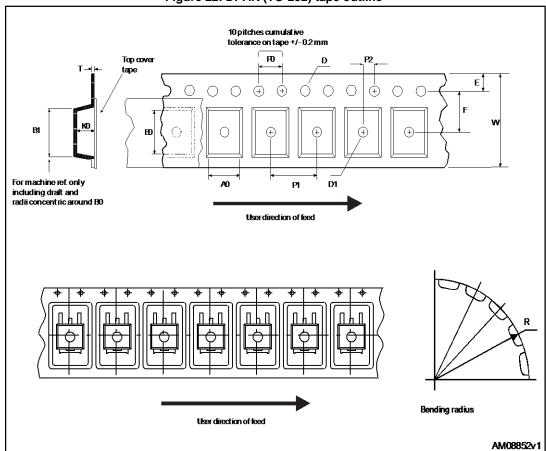
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Figure 21: DPAK (TO-252) recommended footprint (dimensions are in mm)

STD15N50M2AG Package information

4.2 DPAK (TO-252) packing information

Figure 22: DPAK (TO-252) tape outline



40mm min. access hole at slot location С Ν Α G measured Tape slot at hub in core for Full radius tape start 2.5mm min.width

Figure 23: DPAK (TO-252) reel outline

Table 11: DPAK (TO-252) tape and reel mechanical data

AM06038v1

Таре				Reel	
Dim.	m	mm		r	nm
Dim.	Min.	Max.	Dim.	Min.	Max.
A0	6.8	7	А		330
B0	10.4	10.6	В	1.5	
B1		12.1	С	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
Ш	1.65	1.85	N	50	
F	7.4	7.6	Т		22.4
K0	2.55	2.75			
P0	3.9	4.1	Bas	se qty.	2500
P1	7.9	8.1	Bul	k qty.	2500
P2	1.9	2.1			
R	40				
Т	0.25	0.35			
W	15.7	16.3			

STD15N50M2AG Revision history

5 Revision history

Table 12: Document revision history

Date	Revision	Changes
13-Apr-2015	1	First release.
07-May-2016	2	Minor text edits Document status promoted to production data Updated Section 1: "Electrical ratings" Updated Section 2: "Electrical characteristics" Updated Section 2.1: "Electrical characteristics (curves)" Updated Section 4.1: "DPAK (TO-252) type A2 package information"

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